
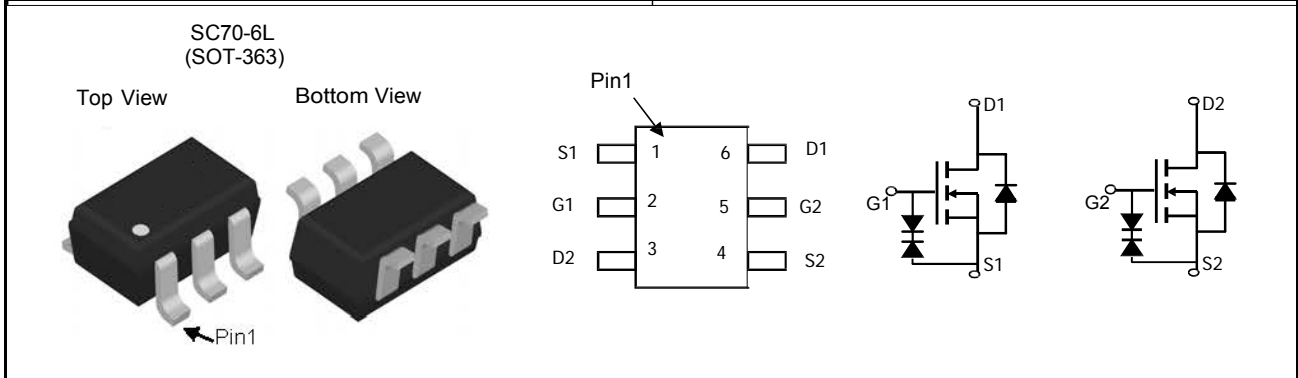


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Dual N-Channel Enhancement Mode Field Effect Transistor

<p><b>General Description</b></p> <p>The HM2302BWKR uses advanced trench technology to provide excellent <math>R_{DS(ON)}</math>, low gate charge and operation at low gate voltages as low as 1.8V, in the small SOT363 package. It can be used for a wide variety of applications, such as load switching, low current inverters and low-voltage DC converters. It is ESD protected.</p>	<p><b>Features</b></p> <ul style="list-style-type: none"> <li><math>V_{DS} (V) = 20V</math></li> <li><math>I_D = 0.9 A (V_{GS} = 4.5V)</math></li> <li><math>R_{DS(ON)} &lt; 270m\Omega (V_{GS} = 4.5V)</math></li> <li><math>R_{DS(ON)} &lt; 30m\Omega (V_{GS} = 2.5V)</math></li> <li><math>R_{DS(ON)} &lt; 450m\Omega (V_{GS} = 1.8V)</math></li> </ul> 
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Absolute Maximum Ratings  $T_A=25^\circ C$  unless otherwise noted

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	$V_{DS}$	20	V
Gate-Source Voltage	$V_{GS}$	$\pm 8$	V
Continuous Drain Current <sup>A</sup>	$T_A=25^\circ C$	0.9	A
		$T_A=70^\circ C$	
Pulsed Drain Current <sup>B</sup>	$I_{DM}$	5	
Power Dissipation <sup>A</sup>	$T_A=25^\circ C$	0.9	W
		$T_A=70^\circ C$	
Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 to 150	$^\circ C$

Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient <sup>A</sup>	$R_{JA}$	120	145	$^\circ C/W$
Maximum Junction-to-Ambient <sup>A</sup>		Steady-State	156	
Maximum Junction-to-Lead <sup>C</sup>	$R_{JL}$	130	150	$^\circ C/W$

Electrical Characteristics ( $T_J=25^{\circ}\text{C}$  unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>STATIC PARAMETERS</b>						
$BV_{DSS}$	Drain-Source Breakdown Voltage	$I_D=250\text{ A}, V_{GS}=0\text{V}$	20			V
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS}=16\text{V}, V_{GS}=0\text{V}$ $T_J=55^{\circ}\text{C}$			1 5	$\mu\text{ A}$
$I_{GSS}$	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm 8\text{V}$			25	$\mu\text{ A}$
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\text{ A}$	0.45		1.2	V
$I_{D(ON)}$	On state drain current	$V_{GS}=4.5\text{V}, V_{DS}=5\text{V}$	5			A
$R_{DS(ON)}$	Static Drain-Source On-Resistance	$V_{GS}=4.5\text{V}, I_D=0.9\text{A}$ $T_J=125^{\circ}\text{C}$		220	270	$\text{m}\Omega$
		$V_{GS}=2.5\text{V}, I_D=0.75\text{A}$		260	330	$\text{m}\Omega$
		$V_{GS}=1.8\text{V}, I_D=0.7\text{A}$		330	450	$\text{m}\Omega$
$g_{FS}$	Forward Transconductance	$V_{DS}=5\text{V}, I_D=0.8\text{A}$		2.6		S
$V_{SD}$	Diode Forward Voltage	$I_S=0.5\text{A}, V_{GS}=0\text{V}$		0.69	1	V
$I_S$	Maximum Body-Diode Continuous Current				0.4	A
<b>DYNAMIC PARAMETERS</b>						
$C_{iss}$	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=10\text{V}, f=1\text{MHz}$		101	120	pF
$C_{oss}$	Output Capacitance		17		pF	
$C_{rss}$	Reverse Transfer Capacitance		14		pF	
$R_g$	Gate resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$		3	4	
<b>SWITCHING PARAMETERS</b>						
$Q_g$	Total Gate Charge	$V_{GS}=4.5\text{V}, V_{DS}=10\text{V}, I_D=0.8\text{A}$		1.57	1.9	nC
$Q_{gs}$	Gate Source Charge		0.13		nC	
$Q_{gd}$	Gate Drain Charge		0.36		nC	
$t_{D(on)}$	Turn-On DelayTime	$V_{GS}=5\text{V}, V_{DS}=10\text{V}, R_L=12.5\text{ }\Omega$ $R_{GEN}=6\text{ }\Omega$		3.2		ns
$t_r$	Turn-On Rise Time		4		ns	
$t_{D(off)}$	Turn-Off DelayTime		15.5		ns	
$t_f$	Turn-Off Fall Time		2.4		ns	
$t_{rr}$	Body Diode Reverse Recovery Time	$I_F=0.8\text{A}, di/dt=100\text{A/ s}$		6.7	8.1	ns
$Q_{rr}$	Body Diode Reverse Recovery Charge	$I_F=0.8\text{A}, di/dt=100\text{A/ s}$		1.6		nC

A: The value of  $R_{JA}$  is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^{\circ}\text{C}$ . The value in any given application depends on the user's specific board design. The current rating is based on the  $t \leq 10\text{s}$  thermal resistance rating.

B: Repetitive rating, pulse width limited by junction temperature.

C: The  $R_{JA}$  is the sum of the thermal impedance from junction to lead  $R_{jL}$  and lead to ambient.

D: The static characteristics in Figures 1 to 6,12,14 are obtained using 80  $\mu\text{s}$  pulses, duty cycle 0.5% max.

E: These tests are performed with the device mounted on 1 in <sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^{\circ}\text{C}$ . The SOA curve provides a single pulse rating.

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## TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

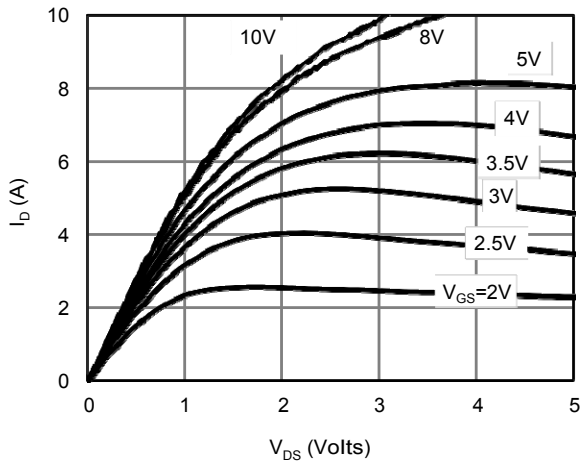


Fig 1: On-Region Characteristics

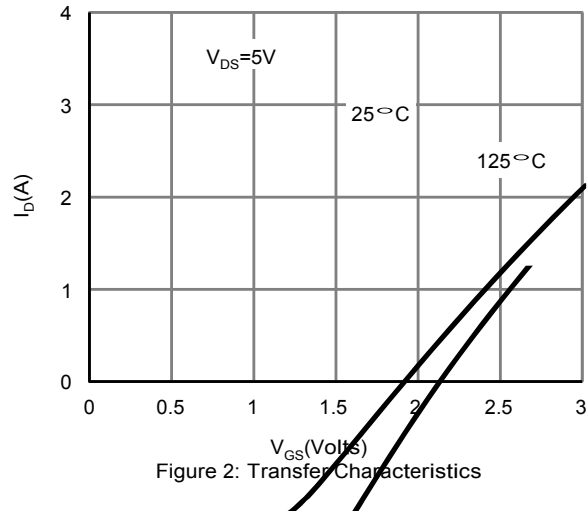


Figure 2: Transfer Characteristics

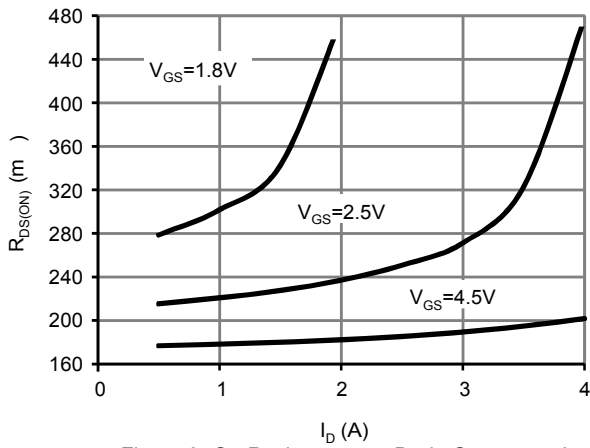


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

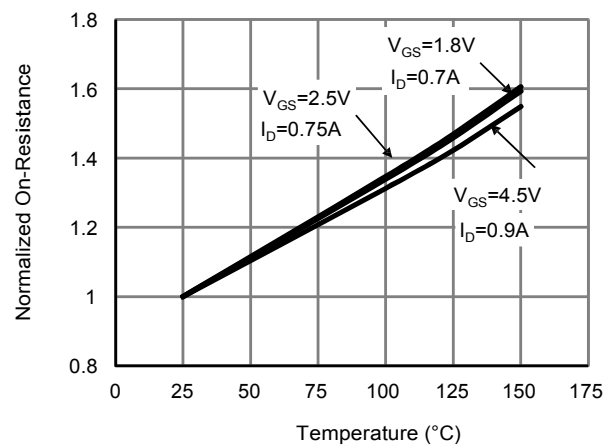


Figure 4: On-Resistance vs. Junction Temperature

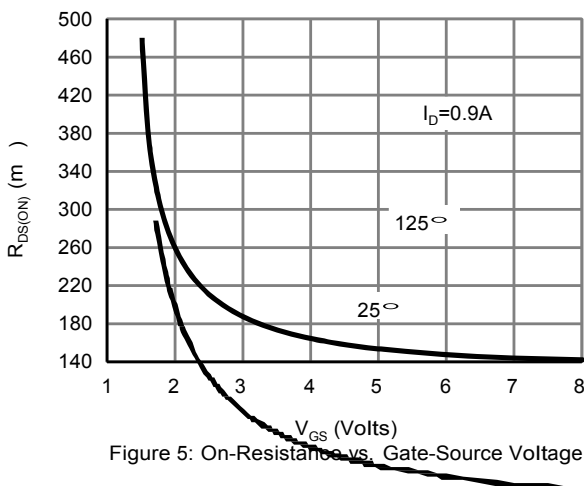


Figure 5: On-Resistance vs. Gate-Source Voltage

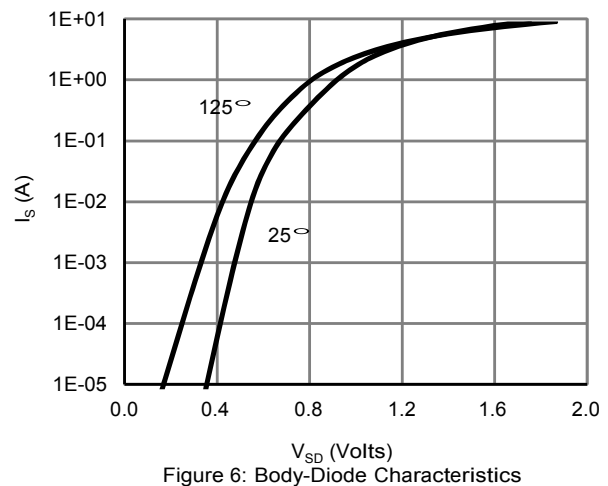


Figure 6: Body-Diode Characteristics

## TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

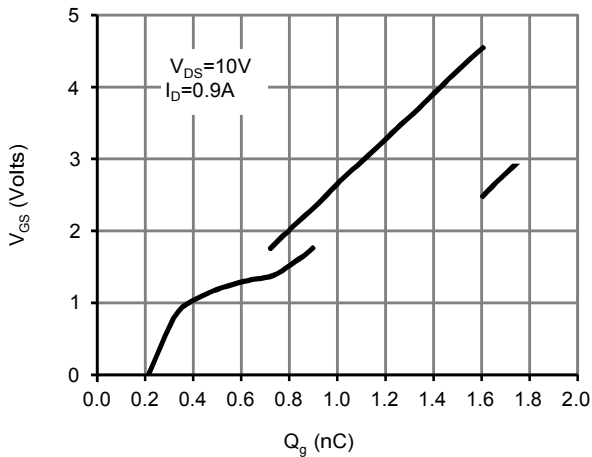


Figure 7: Gate-Charge Characteristics

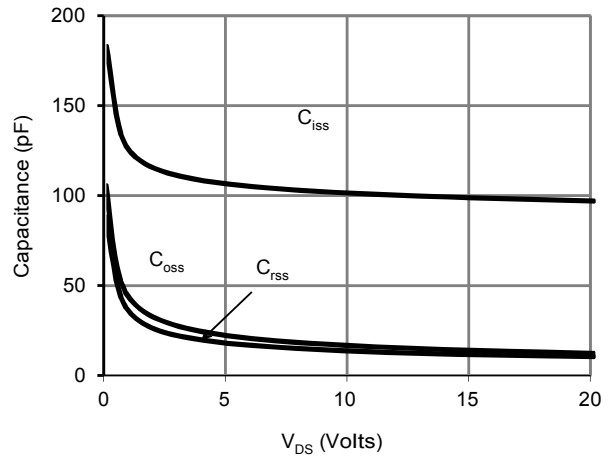


Figure 8: Capacitance Characteristics

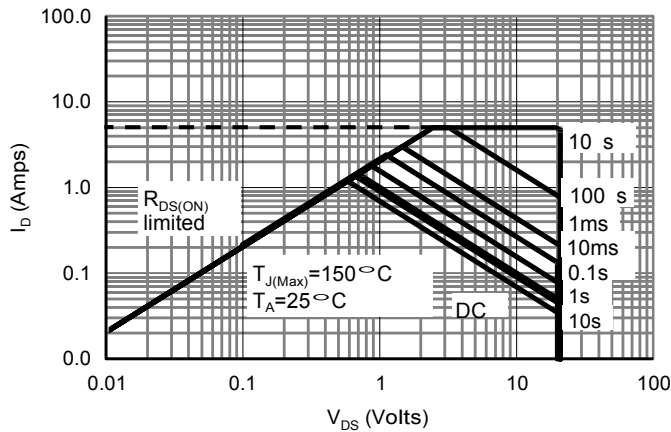


Figure 9: Maximum Forward Biased Safe Operating Area (Note E)

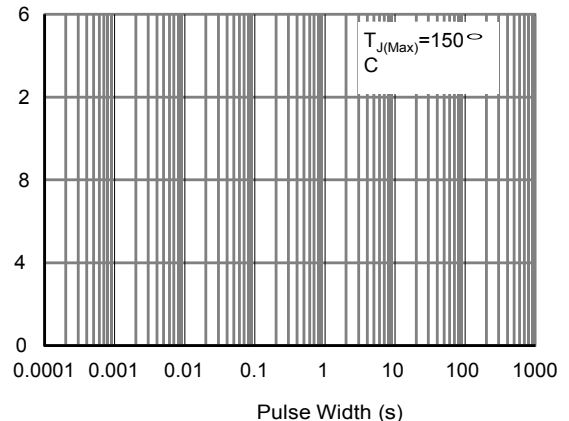


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note E)

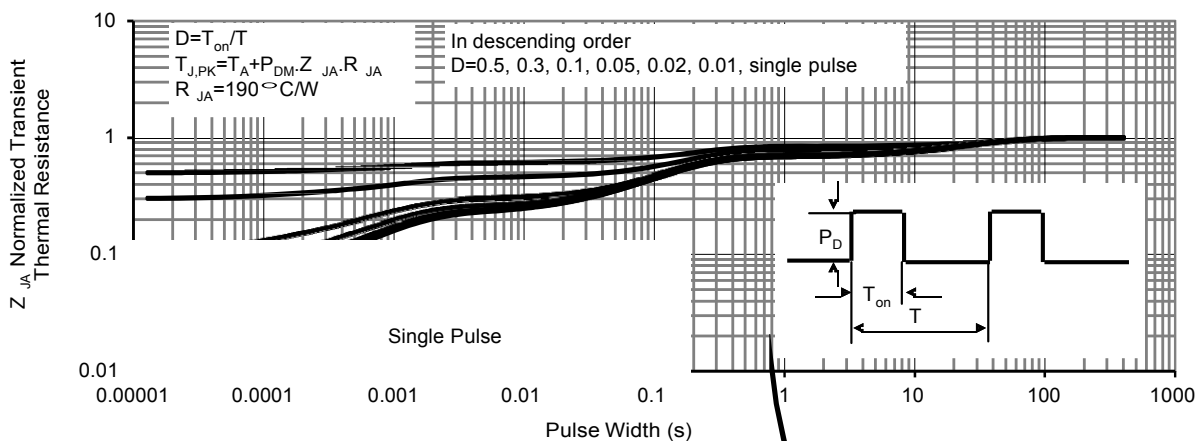
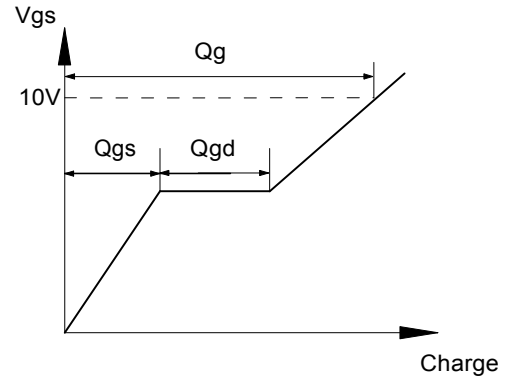
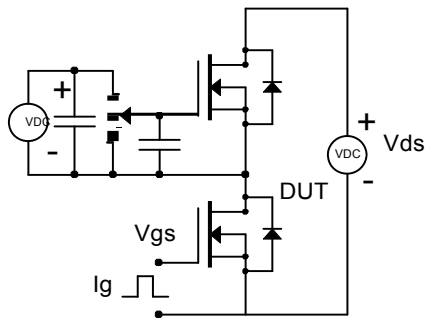
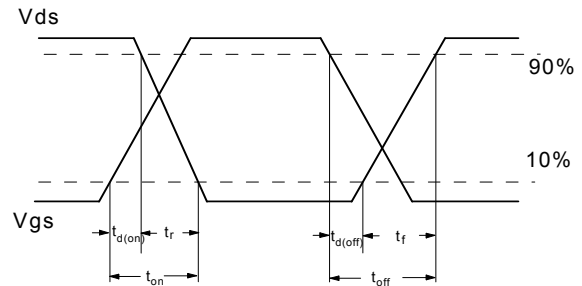
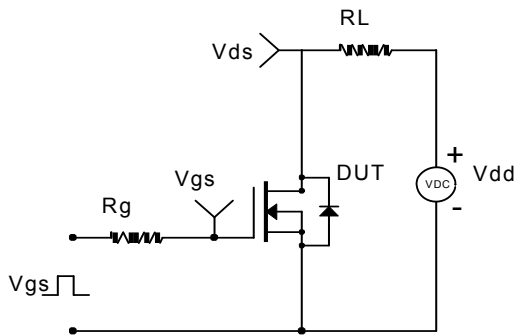


Figure 11: Normalized Maximum Transient Thermal Impedance

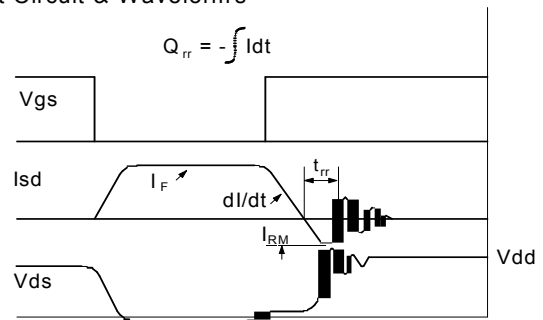
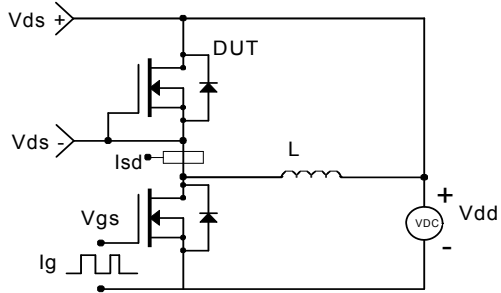
### Gate Charge Test Circuit & Waveform



### Resistive Switching Test Circuit & Waveforms



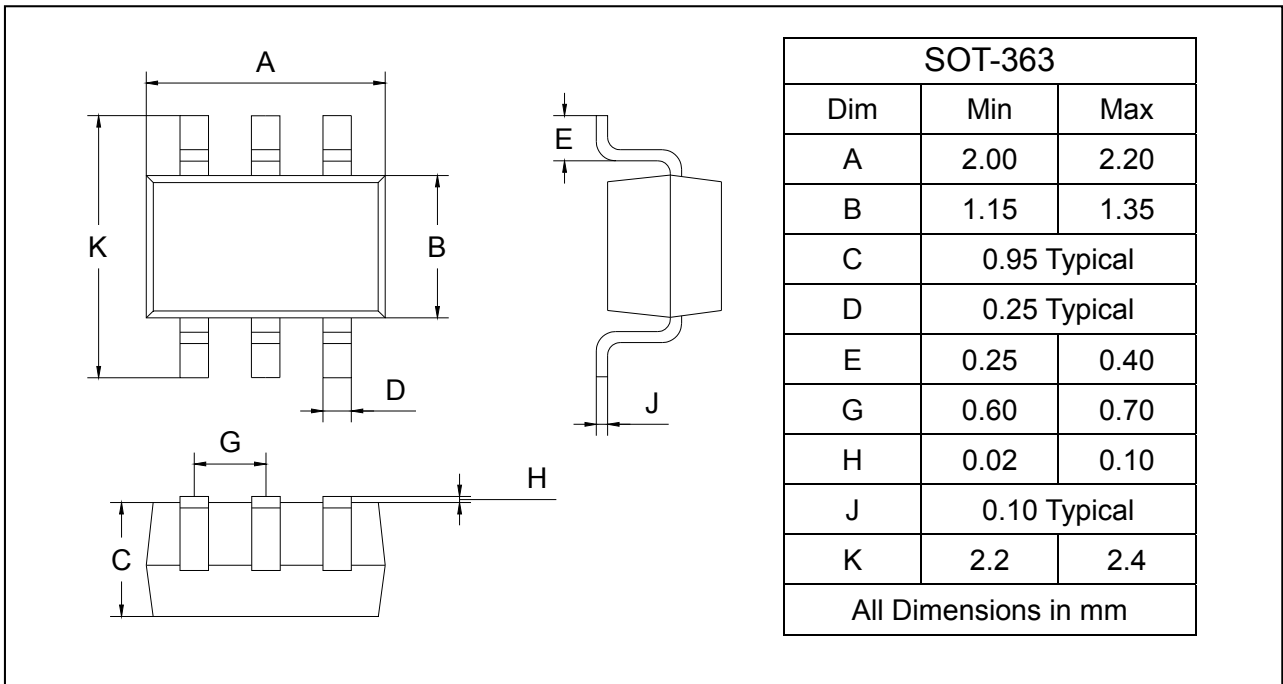
### Diode Recovery Test Circuit & Waveforms



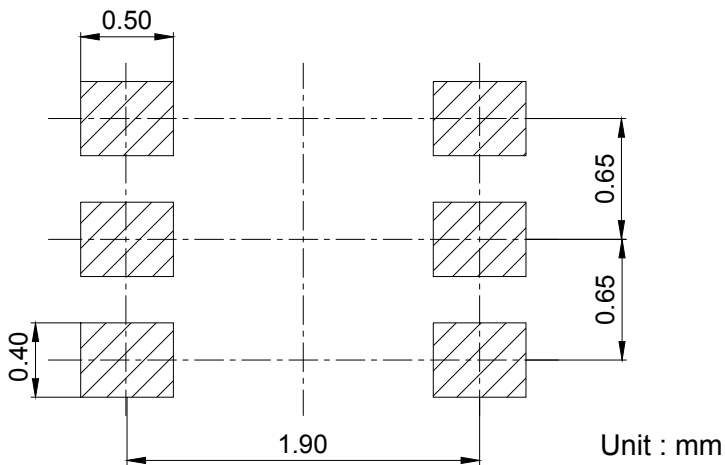
## PACKAGE OUTLINE

Plastic surface mounted package

SOT-363



## SOLDERING FOOTPRINT



## PACKAGE INFORMATION

Device	Package	Shipping
HM2302BWKR	SOT-363	3000/Tape&Reel